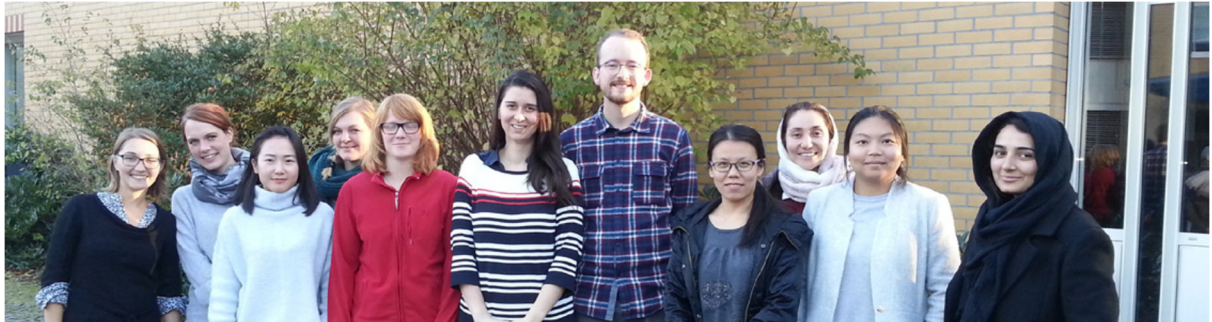


SIMS Course 2017

In 2017, the IAG again supported the short course *Introduction to Secondary Ion Mass Spectrometry in the Earth Science*, which is held each autumn on the campus of the Helmholtz-Zentrum in Potsdam, Germany. This year 17 participants from five countries took part to learn about SIMS and other microanalytical technologies. As usual, it was a very busy week, with the students learning the basics of mass spectrometry, ion optics, data quality assessment and the determination of isotope ratios on samples sizes at or below 200 picograms. Course participants not only visited the large geometry SIMS instrument, but they also had excursions to the femtosecond laser ablation system, field emission electron probe and dual focused ion beam (FIB) laboratories located on the campus.



Some of the participants of the 2017 SIMS short course in Potsdam relax after completing a busy week and the course exam on Friday afternoon